

**Notice of References Cited**

Application/Control No.

10/590,918

Applicant(s)/Patent Under  
Reexamination  
ZOU ET AL.

Examiner

Monique R. Jackson

Art Unit

1787

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,066,581	05-2000	Chivukula et al.	501/12
*	B	US-6,247,799	06-2001	Sakamaki et al.	347/68
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Zhang et al, Self-buffered BaxSr1-xTiO3 films by sol-gel and RF magnetron sputtering method, Materials Research Bulletin 38, 2003, p133-139.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.